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| Notice of References Cited | | Application/Control No. 10/773,451 | Applicant(s)/Patent Under Reexamination SANG ET AL. | |
| | | Examiner KEVIN R. KRUER | Art Unit 1794 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------------|----------------|
| * | A | US-4,874,656 | 10-1989 | Rantanen, Veikko O. | 428/216 |
| * | B | US-5,695,838 | 12-1997 | Tanaka et al. | 428/35.2 |
| * | C | US-2,968,065 | 01-1961 | FREDERICK GRONHOLZ LE ROY | 264/235.8 |
| * | D | US-4,430,135 | 02-1984 | Schmukler et al. | 156/244.11 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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